

Giovanni Mana

List of Publications by Year in descending order

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174
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2,958
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46
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177
all docs

177
docs citations

177
times ranked

881
citing authors

| # | ARTICLE | IF | CITATIONS |
|----|--|-----|-----------|
| 1 | Neutron interference from a split-crystal interferometer. Journal of Applied Crystallography, 2022, 55, 870-875. | 4.5 | 5 |
| 2 | The least informative distribution and correlation coefficient of measurement results. Metrologia, 2021, 58, 015012. | 1.2 | 3 |
| 3 | Measurement of miscut angles in the determination of Si lattice parameters. Metrologia, 2021, 58, 034004. | 1.2 | 3 |
| 4 | Interlaboratory consensus building. Metrologia, 2021, 58, 055002. | 1.2 | 4 |
| 5 | Defocused travelling fringes in a scanning triple-Laue X-ray interferometry setup. Journal of Applied Crystallography, 2021, 54, 1403-1408. | 4.5 | 1 |
| 6 | The fundamental constants of physics and the International System of Units. Rendiconti Lincei, 2021, 32, 655-663. | 2.2 | 3 |
| 7 | The Measurement of the Silicon Lattice Parameter and the Count of Atoms to Realise the Kilogram. Mapan - Journal of Metrology Society of India, 2020, 35, 511-519. | 1.5 | 12 |
| 8 | Gravity and anisotropy effects in the volume determination of Si spheres for the kilogram realisation. Metrologia, 2020, 57, 045004. | 1.2 | 0 |
| 9 | X-ray phase-contrast topography to measure the surface stress and bulk strain in a silicon crystal. Journal of Applied Crystallography, 2020, 53, 1195-1202. | 4.5 | 3 |
| 10 | Corrections of the travelling-fringe period for the interference of aberrated beams. Metrologia, 2019, 56, 055004. | 1.2 | 3 |
| 11 | The LISA interferometer: impact of stray light on the phase of the heterodyne signal. Classical and Quantum Gravity, 2019, 36, 075015. | 4.0 | 6 |
| 12 | Bayesian model selection applied to linear regressions with weighted data. Metrologia, 2019, 56, 025003. | 1.2 | 2 |
| 13 | Telescope jitters and phase noise in the LISA interferometer. Optics Express, 2019, 27, 16855. | 3.4 | 18 |
| 14 | Fake tilts in differential wavefront sensing. Optics Express, 2019, 27, 34505. | 3.4 | 1 |
| 15 | Self-weight effect in the measurement of the volume of silicon spheres. Metrologia, 2018, 55, 294-301. | 1.2 | 2 |
| 16 | Coupling of wavefront errors and jitter in the LISA interferometer: far-field propagation. Classical and Quantum Gravity, 2018, 35, 185013. | 4.0 | 27 |
| 17 | Thermal Gradients in the Si Lattice Parameter Measurement. , 2018, , . | | 0 |
| 18 | Diffraction Error in Laser Interferometry for the Measurement of the ²⁸ Si Lattice Parameter. , 2018, , . | | 0 |

| # | ARTICLE | IF | CITATIONS |
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| 19 | Coupling of wavefront errors and pointing jitter in the LISA interferometer: misalignment of the interfering wavefronts. <i>Classical and Quantum Gravity</i> , 2018, 35, 245002. | 4.0 | 16 |
| 20 | Forward scattering in two-beam laser interferometry. <i>Metrologia</i> , 2018, 55, 222-228. | 1.2 | 3 |
| 21 | Wavefront errors in a two-beam interferometer. <i>Metrologia</i> , 2018, 55, 535-540. | 1.2 | 5 |
| 22 | Avogadro constant measurements using enriched ²⁸ Si monocrystals. <i>Metrologia</i> , 2018, 55, L1-L4. | 1.2 | 24 |
| 23 | Impurities in a ²⁸ Si-Enriched Single Crystal Produced for the Realization of the Redefined Kilogram. <i>Analytical Chemistry</i> , 2017, 89, 6314-6317. | 6.5 | 5 |
| 24 | A new analysis for diffraction correction in optical interferometry. <i>Metrologia</i> , 2017, 54, 559-565. | 1.2 | 11 |
| 25 | Measurement of the ³⁰ Si Mole Fraction in the New Avogadro Silicon Material by Neutron Activation and High-Resolution ³¹ P-Spectrometry. <i>Analytical Chemistry</i> , 2017, 89, 6726-6730. | 6.5 | 9 |
| 26 | A new low-uncertainty measurement of the ³¹ Si half-life. <i>Metrologia</i> , 2017, 54, 410-416. | 1.2 | 5 |
| 27 | Quantification of the Void Volume in Single-Crystal Silicon. <i>Analytical Chemistry</i> , 2016, 88, 11678-11683. | 6.5 | 5 |
| 28 | Optimization of statistical methods for HpGe gamma-ray spectrometer used in wide count rate ranges. <i>Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment</i> , 2016, 824, 99-100. | 1.6 | 2 |
| 29 | Counting atoms. <i>Nature Physics</i> , 2016, 12, 522-522. | 16.7 | 7 |
| 30 | A two thickness interferometer for lattice strain investigations. , 2016, , . | | 1 |
| 31 | Model uncertainty and reference value of the Planck constant. <i>Measurement: Journal of the International Measurement Confederation</i> , 2016, 94, 26-30. | 5.0 | 2 |
| 32 | Diffraction effects in length measurements by laser interferometry. <i>Optics Express</i> , 2016, 24, 6522. | 3.4 | 7 |
| 33 | Density functional theory calculations of the stress of oxidised (1 1 0) silicon surfaces. <i>Metrologia</i> , 2016, 53, 1339-1345. | 1.2 | 11 |
| 34 | Purity of ²⁸ Si-Enriched Silicon Material Used for the Determination of the Avogadro Constant. <i>Analytical Chemistry</i> , 2016, 88, 6881-6888. | 6.5 | 10 |
| 35 | The ellipsoidal nested sampling and the expression of the model uncertainty in measurements. <i>International Journal of Modern Physics B</i> , 2016, 30, 1541002. | 2.0 | 2 |
| 36 | A More Accurate Measurement of the ²⁸ Si Lattice Parameter. <i>Journal of Physical and Chemical Reference Data</i> , 2015, 44, . | 4.2 | 40 |

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| 37 | The Correlation of the ^{28}Si Measurements by Counting ^{28}Si Atoms. Journal of Physical and Chemical Reference Data, 2015, 44, . | 4.2 | 21 |
| 38 | ^{30}Si Mole Fraction of a Silicon Material Highly Enriched in ^{28}Si Determined by Instrumental Neutron Activation Analysis. Analytical Chemistry, 2015, 87, 5716-5722. | 6.5 | 12 |
| 39 | Improved measurement results for the Avogadro constant using a ^{28}Si -enriched crystal. Metrologia, 2015, 52, 360-375. | 1.2 | 143 |
| 40 | Ellipsoidal nested sampling, expression of the model uncertainty and measurement. Journal of Physics: Conference Series, 2015, 626, 012070. | 0.4 | 0 |
| 41 | Design of an interferometric displacement sensor with picometer resolution for the Galileo-Galilei mission. , 2015, , . | | 4 |
| 42 | Lattice strain at c-Si surfaces: a density functional theory calculation. Metrologia, 2015, 52, 214-221. | 1.2 | 13 |
| 43 | Vectorial ray-based diffraction integral. Journal of the Optical Society of America A: Optics and Image Science, and Vision, 2015, 32, 1403. | 1.5 | 24 |
| 44 | Stray capacitances in the watt balance operation: electrostatic forces. Metrologia, 2014, 51, S72-S79. | 1.2 | 2 |
| 45 | The watt-balance operation: a continuous model of the coil interaction with the magnetic field. Metrologia, 2014, 51, S65-S71. | 1.2 | 5 |
| 46 | European metrology research programme: Advance on the realization of the kilogram redefinition. , 2014, , . | | 0 |
| 47 | Assessment of the accuracy of the ^{28}Si (220) plane spacing. , 2014, , . | | 0 |
| 48 | Bayesian estimate of the degree of a polynomial given a noisy data sample. Measurement: Journal of the International Measurement Confederation, 2014, 55, 564-570. | 5.0 | 7 |
| 49 | Interval estimations in metrology. Metrologia, 2014, 51, 191-196. | 1.2 | 5 |
| 50 | The expression of the model uncertainty in measurements. , 2014, , . | | 0 |
| 51 | Instrumental neutron activation analysis of an enriched ^{28}Si single-crystal. Journal of Radioanalytical and Nuclear Chemistry, 2014, 299, 277-282. | 1.5 | 7 |
| 52 | Measuring the divergence of laser beams to correct interferometric displacement measurements. , 2014, , . | | 0 |
| 53 | Neutron activation analysis of the ^{30}Si content of highly enriched ^{28}Si : proof of concept and estimation of the achievable uncertainty. Metrologia, 2014, 51, 354-360. | 1.2 | 5 |
| 54 | Accurate measurements of the Avogadro and Planck constants by counting silicon atoms. Annalen Der Physik, 2013, 525, 680-687. | 2.4 | 21 |

| # | ARTICLE | IF | CITATIONS |
|----|--|-----|-----------|
| 55 | Modelling laser interferometers for the measurement of the Avogadro constant. , 2013, , . | | 1 |
| 56 | Polarization delivery in heterodyne interferometry. Optics Express, 2013, 21, 27119. | 3.4 | 10 |
| 57 | A finite element analysis of surface-stress effects on measurement of the Si lattice parameter. Metrologia, 2013, 50, 243-248. | 1.2 | 13 |
| 58 | The watt-balance operation: magnetic force and induced electric potential on a conductor in a magnetic field. Metrologia, 2013, 50, 164-169. | 1.2 | 6 |
| 59 | An automated resistor network to inspect the linearity of resistance-thermometry measurements. Measurement Science and Technology, 2013, 24, 107001. | 2.6 | 6 |
| 60 | The detection of signals hidden in noise. Metrologia, 2013, 50, 269-276. | 1.2 | 4 |
| 61 | Elemental characterization of the Avogadro silicon crystal WASO 04 by neutron activation analysis. Metrologia, 2012, 49, 696-701. | 1.2 | 14 |
| 62 | The uncertainty of the phase-correction in sphere-diameter measurements. Metrologia, 2012, 49, 479-486. | 1.2 | 18 |
| 63 | Model selection in the average of inconsistent data: an analysis of the measured Planck-constant values. Metrologia, 2012, 49, 492-500. | 1.2 | 35 |
| 64 | Realization of the anticipated definition of the kilogram. , 2012, , . | | 1 |
| 65 | Laser interferometry in the Si lattice-parameter measurement. , 2012, , . | | 0 |
| 66 | Counting the atoms in a ²⁸ Si crystal for a new kilogram definition. Metrologia, 2011, 48, S1-S13. | 1.2 | 160 |
| 67 | The self-weight deformation of an x-ray interferometer. Metrologia, 2011, 48, S50-S54. | 1.2 | 4 |
| 68 | Determination of the Avogadro Constant by Counting the Atoms in a $\langle \text{mml:math xmlns:mml="http://www.w3.org/1998/Math/MathML" display="inline">\langle \text{mml:mmultiscripts} \rangle \langle \text{mml:mi} \rangle \text{Si} \langle \text{mml:mprescripts} \rangle \langle \text{mml:none} \rangle \langle \text{mml:mn} \rangle 28 \langle \text{mml:mn} \rangle \langle \text{mml:mmultiscripts} \rangle \langle \text{mml:math} \rangle \text{Crystal. Physical Review Letters, 2011, 106, 030801.}$ | 7.8 | 183 |
| 69 | Si primary standards for the calibration of ion-current ratios in the molar-mass measurement of natural Si single crystals. Metrologia, 2011, 48, S26-S31. | 1.2 | 18 |
| 70 | Phase corrections in the optical interferometer for Si sphere volume measurements at NMIJ. Metrologia, 2011, 48, S104-S111. | 1.2 | 31 |
| 71 | The isotopic composition of enriched Si: a data analysis. Metrologia, 2011, 48, S32-S36. | 1.2 | 21 |
| 72 | The lattice parameter of the ²⁸ Si spheres in the determination of the Avogadro constant. Metrologia, 2011, 48, S44-S49. | 1.2 | 27 |

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| 73 | Measurement of the $\{2\hat{\alpha}\%2\hat{\alpha}\%0\}$ lattice-plane spacing of a $\langle \sup \rangle 28 \langle /sup \rangle$ Si x-ray interferometer. Metrologia, 2011, 48, S37-S43. | 1.2 | 49 |
| 74 | Uncertainty assessment of Si molar mass measurements. International Journal of Mass Spectrometry, 2010, 289, 6-10. | 1.5 | 11 |
| 75 | The calibration of Si isotope ratio measurements. International Journal of Mass Spectrometry, 2010, 291, 55-60. | 1.5 | 51 |
| 76 | Estimation of the centre of a diffraction peak by triggering the goniometer-angle readings via photon detection. Journal of Applied Crystallography, 2010, 43, 83-88. | 4.5 | 0 |
| 77 | Calibration of a silicon crystal for absolute nuclear spectroscopy. Journal of Applied Crystallography, 2010, 43, 293-296. | 4.5 | 7 |
| 78 | Measurement equations for the determination of the Si molar mass by isotope dilution mass spectrometry. Metrologia, 2010, 47, 460-463. | 1.2 | 31 |
| 79 | Use of Bayesian statistics to reduce the density shift uncertainty in Cesium fountain. , 2010, , . | | 1 |
| 80 | Advances in the measurement of the $\langle \sup \rangle 28 \langle /sup \rangle$ Si lattice parameter. , 2010, , . | | 0 |
| 81 | Status of the $n \langle inf \rangle a \langle /inf \rangle$ determination by counting atoms in silicon crystals. , 2010, , . | | 2 |
| 82 | Bayesian inference of a negative quantity from positive measurement results. , 2009, , . | | 1 |
| 83 | Measurement of the lattice parameter of a silicon crystal. New Journal of Physics, 2009, 11, 053013. | 2.9 | 49 |
| 84 | Bayesian estimate of the zero-density frequency of a Cs fountain. Metrologia, 2009, 46, 629-636. | 1.2 | 3 |
| 85 | Bayesian inference of a negative quantity from positive measurement results. Metrologia, 2009, 46, 267-271. | 1.2 | 13 |
| 86 | The Avogadro constant determination via enriched silicon-28. Measurement Science and Technology, 2009, 20, 092002. | 2.6 | 64 |
| 87 | Observation of a bent crystal-lattice by x-ray interferometry. Optics Express, 2009, 17, 11172. | 3.4 | 7 |
| 88 | Comparison of the INRIM and PTB lattice-spacing standards. Metrologia, 2009, 46, 249-253. | 1.2 | 21 |
| 89 | X-ray and $\hat{1}^3$ -ray propagation in bent crystals with flat and cylindrical surfaces. Acta Crystallographica Section A: Foundations and Advances, 2008, 64, 549-559. | 0.3 | 6 |
| 90 | Influence of surface stress in the determination of the $(2\hat{\alpha}\%2\hat{\alpha}\%0)$ lattice spacing of silicon. Metrologia, 2008, 45, 110-118. | 1.2 | 4 |

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| 91 | Si lattice parameter measurement by centimeter X-ray interferometry. Optics Express, 2008, 16, 16877. | 3.4 | 42 |
| 92 | Silicon lattice-parameter measurements with centimeter x-ray interferometry. , 2008, , . | | 0 |
| 93 | Status of the international effort on the x-ray crystal density work and its progress towards a measurement of the Avogadro constant. , 2008, , . | | 0 |
| 94 | Progress on the GAMS-6 double crystal β -spectrometer. , 2008, , . | | 0 |
| 95 | Measurement of neutron binding energy of ^{36}Cl for a determination of $N_A h$. , 2008, , . | | 0 |
| 96 | On the effect of broadband emission in external-cavity diode-laser interferometry. Measurement Science and Technology, 2007, 18, 1338-1342. | 2.6 | 8 |
| 97 | Considerations on future redefinitions of the kilogram, the mole and of other units. Metrologia, 2007, 44, 1-14. | 1.2 | 114 |
| 98 | Confirmation of the INRiM and PTB Determinations of the Si Lattice Parameter. IEEE Transactions on Instrumentation and Measurement, 2007, 56, 230-234. | 4.7 | 25 |
| 99 | A Possible Solution for the Discrepancy Between the INRiM and NMiJ Values of the Si Lattice-Parameter. IEEE Transactions on Instrumentation and Measurement, 2007, 56, 351-355. | 4.7 | 8 |
| 100 | Uncertainty propagation in non-linear measurement equations. Metrologia, 2007, 44, 246-251. | 1.2 | 18 |
| 101 | The generalized weighted mean of correlated quantities. Metrologia, 2006, 43, S268-S275. | 1.2 | 40 |
| 102 | Aberration effects in two-beam laser interferometers. Journal of the Optical Society of America A: Optics and Image Science, and Vision, 2006, 23, 1951. | 1.5 | 18 |
| 103 | The expression of uncertainty in non-linear parameter estimation. Metrologia, 2006, 43, 396-402. | 1.2 | 22 |
| 104 | On the best fit of a line to uncertain observation pairs. Metrologia, 2005, 42, 376-382. | 1.2 | 14 |
| 105 | Present State of the Avogadro Constant Determination From Silicon Crystals With Natural Isotopic Compositions. IEEE Transactions on Instrumentation and Measurement, 2005, 54, 854-859. | 4.7 | 73 |
| 106 | Effect of recycled light in two-beam interferometry. Review of Scientific Instruments, 2005, 76, 053106. | 1.3 | 10 |
| 107 | Present Status of the a Vogadro Constant Determination from Silicon Crystals with Natural Isotopic Composition. , 2004, , . | | 14 |
| 108 | Measurement of the Avogadro Constant and Mise EN Pratique of an Atomic Definition of the Kilogram by A ^{28}Si Single-Crystal. , 2004, , . | | 0 |

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| 109 | Effects of analyser deformation in scanning x-ray interferometry. Metrologia, 2004, 41, 238-245. | 1.2 | 31 |
| 110 | Measurement repetitions of the Si (220) lattice spacing. Metrologia, 2004, 41, 445-446. | 1.2 | 21 |
| 111 | Measurement repetitions of the Si(220) lattice spacing. Metrologia, 2004, 41, 56-64. | 1.2 | 31 |
| 112 | Effect of lattice strains in the measurement of the (220) lattice spacing of silicon. , 2004, , . | | 0 |
| 113 | Comparison of IMGC and PTB Absolute Determinations of the Si(220) Lattice Spacing. , 2004, , . | | 0 |
| 114 | A Fourier optics approach to the dynamical theory of X-ray diffraction " perfect crystals. Acta Crystallographica Section A: Foundations and Advances, 2004, 60, 40-50. | 0.3 | 9 |
| 115 | A Fourier optics approach to the dynamical theory of X-ray diffraction " continuously deformed crystals. Acta Crystallographica Section A: Foundations and Advances, 2004, 60, 283-293. | 0.3 | 6 |
| 116 | Lattice strain effects in the measurement of the Si lattice parameter by Laue-case double-crystal diffractometry. Journal of Applied Crystallography, 2004, 37, 773-777. | 4.5 | 32 |
| 117 | Joint IMGC-NMIJ Measurement of the Si (220) Lattice Spacing. , 2004, , . | | 0 |
| 118 | A two-axis tip-tilt platform for x-ray interferometry. Measurement Science and Technology, 2003, 14, 717-723. | 2.6 | 11 |
| 119 | Accuracy assessment of data analysis in absolute gravimetry. IEEE Transactions on Instrumentation and Measurement, 2003, 52, 500-503. | 4.7 | 3 |
| 120 | Retrieval of the phase profile of digitized interferograms. Journal of Optics, 2003, 5, 418-424. | 1.5 | 8 |
| 121 | Propagation of error analysis in a total least-squares estimator in absolute gravimetry. Metrologia, 2002, 39, 489-494. | 1.2 | 8 |
| 122 | Propagation of error analysis in least-squares procedures with second-order autoregressive measurement errors. Measurement Science and Technology, 2002, 13, 1505-1511. | 2.6 | 8 |
| 123 | Convective forces in high precision mass measurements. Measurement Science and Technology, 2002, 13, 13-20. | 2.6 | 14 |
| 124 | <title>Applications of x-ray interferometry in metrology and phase-contrast imaging</title>. , 2002, , . | | 3 |
| 125 | Accuracy of laser beam center and width calculations. Applied Optics, 2001, 40, 1378. | 2.1 | 10 |
| 126 | Location accuracy limitations for CCD cameras. Astronomy and Astrophysics, 2001, 367, 362-370. | 5.1 | 22 |

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| 127 | Combined optical and X-ray interferometry for high-precision dimensional metrology. Proceedings of the Royal Society A: Mathematical, Physical and Engineering Sciences, 2000, 456, 701-729. | 2.1 | 70 |
| 128 | Measuring small lattice distortions in Si-crystals by phase-contrast x-ray topography. Journal Physics D: Applied Physics, 2000, 33, 2678-2682. | 2.8 | 10 |
| 129 | Light Bounces in Two-Beam Scanning Laser Interferometers. Japanese Journal of Applied Physics, 2000, 39, 2870-2875. | 1.5 | 10 |
| 130 | Simulation of the thermoelastic behavior of an LLL x-ray interferometer. Review of Scientific Instruments, 2000, 71, 1716-1722. | 1.3 | 6 |
| 131 | A Fizeau interferometer for astrometry in space: the metrology point of view. Measurement Science and Technology, 1999, 10, 1254-1260. | 2.6 | 6 |
| 132 | Optically polished surfaces parallel to the (220) lattice planes of silicon monocrystals. Measurement Science and Technology, 1999, 10, 549-553. | 2.6 | 4 |
| 133 | Scanning X-ray interferometry and the silicon lattice parameter: towards relative uncertainty?. European Physical Journal B, 1999, 9, 225-232. | 1.5 | 33 |
| 134 | A Fourier optics model of two-beam scanning laser interferometers. European Physical Journal D, 1999, 5, 433-440. | 1.3 | 28 |
| 135 | <title>Enabling interferometry technologies for the GAIA astrometric mission</title>. , 1999, , . | | 0 |
| 136 | Sphericity analysis of solid density standards. Review of Scientific Instruments, 1998, 69, 1383-1390. | 1.3 | 7 |
| 137 | Multigrid Monte Carlo simulation via XYembedding. II. Two-dimensional SU(3) principal chiral model. Physical Review D, 1997, 55, 3674-3741. | 4.7 | 15 |
| 138 | Quantized positioning of x-ray interferometers. Review of Scientific Instruments, 1997, 68, 17-22. | 1.3 | 21 |
| 139 | Lattice parameter and thermal expansion of monocrystalline silicon. Journal of Applied Physics, 1997, 82, 5396-5400. | 2.5 | 33 |
| 140 | Beam-astigmatism in laser interferometry. IEEE Transactions on Instrumentation and Measurement, 1997, 46, 196-200. | 4.7 | 10 |
| 141 | Scanning X-ray interferometry over a millimeter baseline. IEEE Transactions on Instrumentation and Measurement, 1997, 46, 576-579. | 4.7 | 13 |
| 142 | Simulation of Monolithic Silicon LLL Scanning X-Ray Interferometer. Japanese Journal of Applied Physics, 1997, 36, 5356-5360. | 1.5 | 2 |
| 143 | Scanning LLL x-ray interferometry. Zeitschrift für Physik B-Condensed Matter, 1997, 102, 189-196. | 1.1 | 11 |
| 144 | Scanning LLL x-ray interferometry. Zeitschrift für Physik B-Condensed Matter, 1997, 102, 197-206. | 1.1 | 18 |

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| 145 | The (220) lattice spacing of silicon. IEEE Transactions on Instrumentation and Measurement, 1995, 44, 526-529. | 4.7 | 39 |
| 146 | A new determination of $N/\text{sub } A/$. IEEE Transactions on Instrumentation and Measurement, 1995, 44, 538-541. | 4.7 | 68 |
| 147 | The Avogadro constant. Rivista Del Nuovo Cimento, 1995, 18, 1-23. | 5.7 | 29 |
| 148 | Volume of Quasi-spherical Solid Density Standards. Metrologia, 1994, 31, 289-300. | 1.2 | 21 |
| 149 | Observation of Fresnel diffraction in a two-beam laser interferometer. Physical Review A, 1994, 49, 2167-2173. | 2.5 | 19 |
| 150 | Measurement of the silicon (220) lattice spacing. Physical Review Letters, 1994, 72, 3133-3136. | 7.8 | 105 |
| 151 | The Lattice Parameter of Silicon: A Survey. Metrologia, 1994, 31, 203-209. | 1.2 | 27 |
| 152 | International Workshop on the Avogadro Constant and the Representation of the Silicon Mole. Metrologia, 1994, 31, 155-155. | 1.2 | 3 |
| 153 | A displacement and angle interferometer with subatomic resolution. Review of Scientific Instruments, 1993, 64, 3076-3081. | 1.3 | 48 |
| 154 | Servopositioning with picometer resolution. Review of Scientific Instruments, 1993, 64, 168-173. | 1.3 | 23 |
| 155 | Phase Holonomy in Optical Interferometry. Journal of Modern Optics, 1992, 39, 2053-2074. | 1.3 | 18 |
| 156 | Silicon lattice constant: limits in IMGC X-ray/optical interferometry. IEEE Transactions on Instrumentation and Measurement, 1991, 40, 98-102. | 4.7 | 22 |
| 157 | Accuracy assessment of a least-squares estimator for scanning X-ray interferometry. Measurement Science and Technology, 1991, 2, 725-734. | 2.6 | 30 |
| 158 | Phase Modulation in High-resolution Optical Interferometry. Metrologia, 1991, 28, 455-461. | 1.2 | 36 |
| 159 | Non-Linear Analysis of the Elastic Behaviour of a Translation Device for X-Ray Interferometry. Metrologia, 1989, 26, 219-227. | 1.2 | 13 |
| 160 | Diffraction Effects in Optical Interferometers Illuminated by Laser Sources. Metrologia, 1989, 26, 87-93. | 1.2 | 33 |
| 161 | Lattice bending in x-ray interferometers. European Physical Journal B, 1989, 76, 25-31. | 1.5 | 9 |
| 162 | Progress at IMGC in the absolute determination of the silicon d. IEEE Transactions on Instrumentation and Measurement, 1989, 38, 210-216. | 4.7 | 59 |

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| 163 | Electromagnetic quantities and units derived from classical relativistic electrodynamics. American Journal of Physics, 1988, 56, 1081-1085. | 0.7 | 0 |
| 164 | On the Construction of a Zerodur Translation Device for X-Ray Interferometric Scanning. Metrologia, 1986, 22, 55-63. | 1.2 | 17 |
| 165 | Beam-astigmatism in laser interferometry. , 0, , . | | 0 |
| 166 | Scanning X-ray interferometry over a millimeter baseline. , 0, , . | | 0 |
| 167 | Critical aspects of scanning X-ray/optical interferometry. , 0, , . | | 0 |
| 168 | Sub-nanometric metrology for high resolution astrometric interferometry. , 0, , . | | 0 |
| 169 | Active distance stabilization of large bodies with picometer repeatability. , 0, , . | | 2 |
| 170 | A new scanning X-ray interferometer [for basic physical constants determination]. , 0, , . | | 0 |
| 171 | Analysis of lattice-strain effects in LLL X-ray interferometers by Takagi equations. , 0, , . | | 0 |
| 172 | The Si-route to the Avogadro constant: new measurements of the molar volume and lattice parameter in an integrated international approach. , 0, , . | | 0 |
| 173 | Remeasurement of the (220) lattice spacing of silicon. , 0, , . | | 0 |
| 174 | The kilogram: inertial or gravitational mass?. Metrologia, 0, , . | 1.2 | 3 |